International
Standard

ISO 11505

Surface chemical analysis — General procedures for quantitative compositional depth profiling by glow discharge optical emission spectrometry

Analyse chimique des surfaces — Modes opératoires généraux pour le profilage en profondeur compositionnel quantitatif par spectrométrie d'émission optique à décharge luminescente

Second edition
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Foreword

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This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*, Subcommittee SC 8, *Glow discharge spectroscopy*.

This second edition cancels and replaces the first edition (ISO11505:2012), which has been technically revised.

The main changes are as follows:

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- the listed types of array detectors have been updated;
- advances in measurement techniques and apparatus have expanded the applicable sample sizes, and modifications have been made to optimize the optics, vacuum and detection systems;
- the text “setting of the high voltage for the detectors” is replaced with “setting of the parameters for detector sensitivity” throughout the documents;
- the instructions to optimize the crater shape has been changed from mandatory to optional.

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